



Certificate of Analysis

IARM 2H

AISI 304 / UNS S30400

Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

Al	0.0034 ± 0.0008	As	0.007 ± 0.001	B	0.0005 ± 0.0002	C	0.050 ± 0.001
Co	0.130 ± 0.002	Cr	18.28 ± 0.02	Cu	0.437 ± 0.005	Mn	1.86 ± 0.01
Mo	0.264 ± 0.004	N	0.080 ± 0.001	Nb	0.0099 ± 0.0006	Ni	8.23 ± 0.03
O	0.007 ± 0.002	P	0.0320 ± 0.0007	S	0.0278 ± 0.0007	Si	0.248 ± 0.009
Sn	0.011 ± 0.001	Ta	0.006 ± 0.002	Ti	0.0019 ± 0.0005	V	0.066 ± 0.002
W	0.022 ± 0.001	Zr	0.003 ± 0.002				

Indicative Values listed in ppm

Ca (21)	Ce (<50)	Mg (<250)	Pb (<30)	Sb (18)	Se (<300)	Zn (<60)
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Description and Intended Use

This CRM may come in the form of a solid disc or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Interpretation of Data

1. Certified values listed reflect analysis results submitted by qualified analytical laboratories using a combination of methods and instrumentation that emulate actual methods and instrumental techniques currently utilized in the analytical community, and are reported as wt% unless otherwise noted.
2. This material was tested using both the solid disks and chips prepared from individual sections of bar. The certified values are considered representative of the overall average composition of the material.
3. Any data reported and enclosed by a parentheses () is a "best estimate" and is not certified. This data could not be quantified sufficiently for certification. It was, however, reported by enough laboratories to be considered as potentially present in the matrix of the material being examined.
4. "Provisional Certificate of Analysis" reports values that support a fully certified reference material; it also indicates that values may be in a continued process of statistical evaluation and are subject to change.
5. Chips are not certified for Oxygen analysis.



The following data and accompanying statements represent all pertinent information reported in the ILAP as it applies to the chemical characterization of this material.

	Al	As	B	C	Ca	Ce	Co	Cr	Cu	Mg	Mn	Mo	N	Nb	Ni	O
1	0.0009	0.0037	0.000065	0.047	0.0016	<0.0001	0.126	18.20	0.424	0.00003	1.834	0.2497	0.0772	0.0085	8.117	0.0035
2	0.0014	0.0059	0.0002	0.04745	0.0018	<0.005	0.1264	18.234	0.427	0.0002	1.834	0.2542	0.0777	0.0089	8.178	0.005
3	0.0027	0.0071	0.000325	0.049	0.0022		0.1267	18.24	0.429	0.022	1.845	0.258	0.0777	0.009	8.1788	0.0051
4	0.0027	0.0074	0.0004	0.049	0.0023		0.127	18.2626	0.43		1.846	0.258	0.0785	0.0093	8.21	0.0054
5	0.003	0.0074	0.0005	0.0493	0.0024		0.129	18.2665	0.432		1.849	0.2625	0.0789	0.0099	8.213	0.006
6	0.0031	0.0079	0.0005	0.0495			0.129	18.2693	0.4346		1.853	0.2628	0.079	0.0099	8.215	0.0071
7	0.0032	0.0083	0.0005	0.05			0.1294	18.27	0.435		1.86	0.2628	0.0796	0.01	8.227	0.0079
8	0.0038	0.0084	0.00063	0.0506			0.1298	18.2885	0.4363		1.87	0.263	0.0799	0.01	8.234	0.00847
9	0.0039		0.0007	0.051			0.132	18.291	0.438		1.879	0.263	0.0804	0.01	8.238	0.0111
10	0.004		0.0009	0.0511			0.132	18.293	0.441		1.8798	0.27	0.081	0.0101	8.245	
11	0.0041			0.052			0.132	18.30	0.446		1.88	0.27	0.0812	0.0106	8.2624	
12	0.0042			0.052			0.133	18.30	0.4461		1.8809	0.271	0.08279	0.012	8.27	
13	0.0066			0.0523			0.1358	18.31	0.447		1.883	0.273	0.0832		8.29	
14				0.0527				18.327	0.448		1.897	0.274			8.29	
15																
Mean	0.0034	0.007	0.0005	0.05	0.0021		0.13	18.28	0.437	0.01	1.86	0.264	0.08	0.0099	8.23	0.007
STDV.	0.001	0.002	0.0002	0.002	0.0003		0.003	0.03	0.008	0.01	0.02	0.007	0.002	0.0009	0.05	0.002
Certified	0.0034	0.007	0.0005	0.050	(0.0021)	(<0.005)	0.130	18.28	0.437	(<0.025)	1.86	0.264	0.080	0.0099	8.23	0.007
95% C.I.	0.0008	0.001	0.0002	0.001			0.002	0.02	0.005		0.01	0.004	0.001	0.0006	0.03	0.002
Methods	O,I	O,IM,I,A	O,I	O,C	O,I	O,IM	X,O,I	X,W,O,I	X,O,I	O,IM	X,O,I	X,O,I	O,F	X,O,I	X,O,I	O,F

	P	Pb	S	Sb	Se	Si	Sn	Ta	Ti	V	W	Zn	Zr			
1	0.03	0.00003	0.026	0.0016	0.000007	0.213	0.0082	0.003	0.001	0.06	0.0199	0.0002	0.0001			
2	0.03	0.00044	0.026	0.0017	0.00006	0.2205	0.0098	0.0046	0.001	0.0615	0.02005	0.0004	0.0001			
3	0.031	0.0011	0.0262	0.0018	0.00006	0.2435	0.0102	0.0061	0.0012	0.065	0.0217	0.004	0.0013			
4	0.0315	0.0021	0.027	0.0019	0.0049	0.245	0.01035	0.0068	0.0012	0.0658	0.0218	0.006	0.0018			
5	0.0317	0.0026	0.0272	0.002	0.03	0.2466	0.0109	0.007	0.0014	0.0658	0.022	<0.00001	0.0025			
6	0.0319		0.0273			0.247	0.011	0.0083	0.0016	0.066	0.022		0.0034			
7	0.0319		0.0275			0.249	0.01185		0.0018	0.0663	0.022		0.006			
8	0.032		0.0279			0.2521	0.012		0.002	0.0675	0.022		0.0077			
9	0.032		0.02867			0.254	0.012		0.002	0.0678	0.023					
10	0.0321		0.0288			0.257	0.012		0.0021	0.0678	0.025					
11	0.0324		0.0289			0.257	0.0124		0.0023	0.068						
12	0.033		0.0289			0.2596	0.0125		0.0034	0.068						
13	0.0334		0.029			0.26	0.015		0.004	0.069						
14	0.0348		0.0295			0.266				0.072						
15																
Mean	0.032	0.001	0.0278	0.0018	0.01	0.248	0.011	0.006	0.0019	0.066	0.022	0.003	0.003			
STDV.	0.001	0.001	0.001	0.0002	0.01	0.01	0.002	0.002	0.0009	0.003	0.001	0.003	0.003			
Certified	0.0320	(<0.003)	0.0278	(0.0018)	(<0.03)	0.248	0.011	0.006	0.0019	0.066	0.022	(<0.006)	0.003			
95% C.I.	0.0007		0.0007			0.009	0.001	0.002	0.0005	0.002	0.001		0.002			
Methods	X,O,I	O,IM,A	O,C	O,IM,I,A	O,IM,A	X,O,I	X,O,IM,A	X,O,IM	X,O,I	X,O,I	X,O,I	O,IM,A	X,O,IM,I			

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES



Participating Laboratories

Certified Alloy Products, Inc.
SPECTRO Analytical Instruments Inc.
AADFW, Inc.
Ellwood National Steel
Cronimet Specialty Metals USA, Inc.
Crucible Industries

Long Beach, CA
Mahwah, NJ
Euleess, TX
Irvine, PA
Wheatland, PA
Syracuse, NY

ATI Specialty Materials, Lockport
Laboratory Testing, Inc.
Laboratorio Prove Materiali S. Marco srl
Davis Alloys Manufacturing, LLC
MetalTek International, Inc.
Exova - Gary

Lockport, NY
Hatfield, PA
Schio, Italy
Sharpville, PA
Waukesha, WI
Gary, IN

Traceability

Members of the "Inter-Laboratory Analysis Program" (ILAP) validate test methods and instrument performance utilizing SRMs, CRMs, and RMs produced by recognized Certifying Bodies. The specific SRMs, CRMs, and RMs applicable to the material covered by this certificate are:

ALPHA AR1650	ALPHA AR654	ALPHA AR661	ALPHA AR870	ALPHA AR871	ALPHA AR881	ALPHA AR882	ALPHA AR883	ALPHA AR890
ASTM 0041	ASTM 42	ASTM 521	BAS 461	BCS 346	BS 60C	BS 81D	BS 81G	BS 81P
BS 81T	BS 81V	BS 81V-1	BS 83F	BS 847942	BS 8620B	IARM 162A	IARM 162B	IARM 162C
IARM 234B	IARM 241B	IARM 2A	IARM 2C	IARM 2E	IARM 2F	IARM 2G	IARM 35J	IARM 5F
LECO 501-502	LECO 501-503	LECO 501-644	LECO 501-675	LECO 502-197	LECO 502-328	MBH 13X12534U	MBH 13X30403	NIST 1152
NIST 1154	NIST 121D	NIST 1763A	NIST 293	NIST 3103A	NIST 3107	NIST 3109A	NIST 3131A	NIST 3137
NIST 3149	NIST 3155	NIST 3162A	NIST 3163	NIST 3165	NIST 361	NIST 363	NIST 897	NIST 898
NIST 899								

Homogeneity and Uncertainty

"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity is also determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S = Standard deviation, t =t-value at 95% CI, and n = number of observations.

$$1. N_{min} = \max(10, \sqrt[3]{N_{prod}})$$

$$2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

The International Standards Organization (ISO) definitions, expressed in ISO Guide 30–1992 list the following:

Certifying Body: Any technically competent body (organization or firm, public or private) that issues a reference material certificate with the information detailed in ISO Guide 31. The only generally accepted certifying body in the United States for primary standards or Standard Reference Materials (SRM) is the U. S. Department of Commerce, National Institute of Standards & Technology (NIST), Gaithersburg, MD. All other certifying bodies in the United States produce Reference Materials (RM) or Certified Reference Materials (CRM).

Reference Material (RM): Material or substance, with one or more property values that are sufficiently homogeneous and well established, to be used for the calibration of an apparatus, the assessment of a measurement method, or for assigning values to materials.

Certified Reference Material (CRM): Reference material, accompanied by a certificate, with one or more property values certified by a procedure, which establishes its traceability to an accurate realization of the unit in which the property values are expressed, and for which each certified value is accompanied by an uncertainty at a stated level of confidence.

Inter-Laboratory Analysis Program (ILAP): ASTM Standard E691-87 applies to inter-laboratory studies to "Determine the Precision of a Single Test Method", but also outlines a well thought out and logical plan for conducting an inter laboratory program involving multiple analytical techniques. Therefore, the guidelines established in ASTM E691-87 were applied to all aspects of this inter laboratory program, including the protocols for planning, handling, analysis and treatment of resulting data.

Methods of Analysis: The "Inter Laboratory Analysis Program" analyzes a wide variety of materials, and as a result, no single analytical method would provide optimum analytical results. Therefore, a combination of ASTM Standard Methods for classical wet chemistry, ICP, AA, Optical Emission, X-Ray spectrometric, and other accepted methods were used to produce analytical data. Carbon, Sulfur, Nitrogen, and Oxygen results were supplied from combustion and OE instrument procedures.

Expiration of Certification: The certification of this IARM is valid indefinitely, within the uncertainty specified, provided the IARM is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the IARM is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Instructions for Use: The test surface is on the side opposite to the labeled surface, which includes the IARM number. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. **Chips are not to be used for Oxygen analysis.**

Selection of Materials: A "batch" or "series" is defined as a continuous length of bar produced from a single heat. The majority of IARM materials are in wrought condition; other methods of manufacture are utilized if necessary. ILAP samples are removed from equal sections from the total length of the bar. A portion of each section is converted to chips and a thin (pin) disk for analysis by classical wet chemistry, ICP, AA, and combustion procedures, and the balance remains as a thick disk for OES and X-Ray analysis.



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